

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 10/634,374 | Applicant(s)/Patent Under Reexamination KOBUYA ET AL. | |
| | Examiner Tuan C To | Art Unit 3663 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| | A | US-2002/0049064 | 04-2002 | Banno, Satoshi | 455/456 |
| | B | US-2001/0050631 | 12-2001 | Takenaga, Takashi | 342/357.13 |
| | C | US-6,480,804 | 11-2002 | Maeda et al. | 702/150 |
| | D | US-2002/0090953 | 07-2002 | Aburai et al. | 455/456 |
| | E | US-2002/0123329 | 09-2002 | Murray, Brad A. | 455/414 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.